

SUPPLY-CHAIN PERFORMANCE SUBCOMMITTEE MINUTES

Date: Jan 24, 2007
Location: Volterra, Fremont, California USA
Time: 1:30pm - 2:30pm (PST)

Participants:

FSA (Chelsea Boone)
Dan Wark
Steve Joyce
Mark Ashton
Ed Pausa
Eelco Bergman
Grant Thornton Representative

Meeting Purpose:

- To discuss Q4 2006 Wafer/Assembly & Test Pricing Survey Results
- Review participant comments
- Address new concerns/modifications

Actions Completed/Items Discussed:

- Are there any outliers in the Q4 2006 interactive results (wafer, test, assembly) that need to be deleted?
- Should any of the data that was confirmed by Grant Thornton be deleted?
- What new concerns/requests have been voiced by our participants/subscribers?
- Are there any additional questions/features that need to be added to the Survey/Report?

End Result/Conclusions:

- Need to lower filter to a minimum value of \$0.002 for all BGA families represented in the assembly survey.
- Lower filter to a minimum value of \$900 for 200mm/CMOS/0.15 & 0.13.
- Need to delete maximum value of \$28.0600 and max value of \$0.65000 in the assembly results.
- Need to verify company data by having Grant Thornton view and confirm pricing data using company Pos (random sample).
- Need new mask cost filters. FSA will obtain new mask cost filter threshold by geometry from Grant Thornton to develop new filters.
- Graphs in the report should now reflect average and median price.
- Avg Mask Set Cost will now be a straight average, not weighted.
- FSA will survey companies to see if they are receiving value from the test section.
- The next subcommittee meeting will be held **the end of Feb** 2007 at Volterra. A meeting time will be announced soon.